

**Search Notes**

Application/Control No.

10/725,309

Examiner

Quynh H. Nguyen

Applicant(s)/Patent under  
Reexamination

CHANG ET AL.

Art Unit

2614

**SEARCHED**

Class	Subclass	Date	Examiner
379	220.01 387.01 201.01 93.01	3/27/2007	QN
above	updated	7/9/2007	QN
370	260	7/8/07	QN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
379	220.01 387.01 201.01 93.01	7/9/07	QN
370	260	7/8/07	QN
Interference searched history printout		7/9/07	QN

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search includes search in USPat,USPub,Derwen,JPO, and EPO databases	3/27/2007	QN
Inventor name search via PALM database	3/27/2007	QN